Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/604,277	BEDNAR ET AL.	
Examiner	Art Unit	
Binh C. Tat	2825	

Subclass 8	Date	Examiner
8		
	2/3/2006	вт
	<u> </u>	
	8	8 2/3/2006

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	7, 10			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST SEARCH	2/3/2006	вт	
IEEE	2/3/2006	вт	
	=		